

<b>Notice of References Cited</b>	Application/Control No. 10/080,411	Applicant(s)/Patent Under Reexamination ANDOH, TSUYOSHI	
	Examiner Andrew L. Snizek	Art Unit 2651	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,408,338 B1	06-2002	Moon et al.	709/231
	B	US-6,553,180 B1	04-2003	Kikuchi et al.	386/95
	C	US-5,999,933 A	12-1999	Mehta, Abhay	707/100
	D	US-2001/0015944 A1	08-2001	Takahashi et al.	369/53.24
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP407141837A	06-1995	Japan	Nakamura et al.	-----
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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